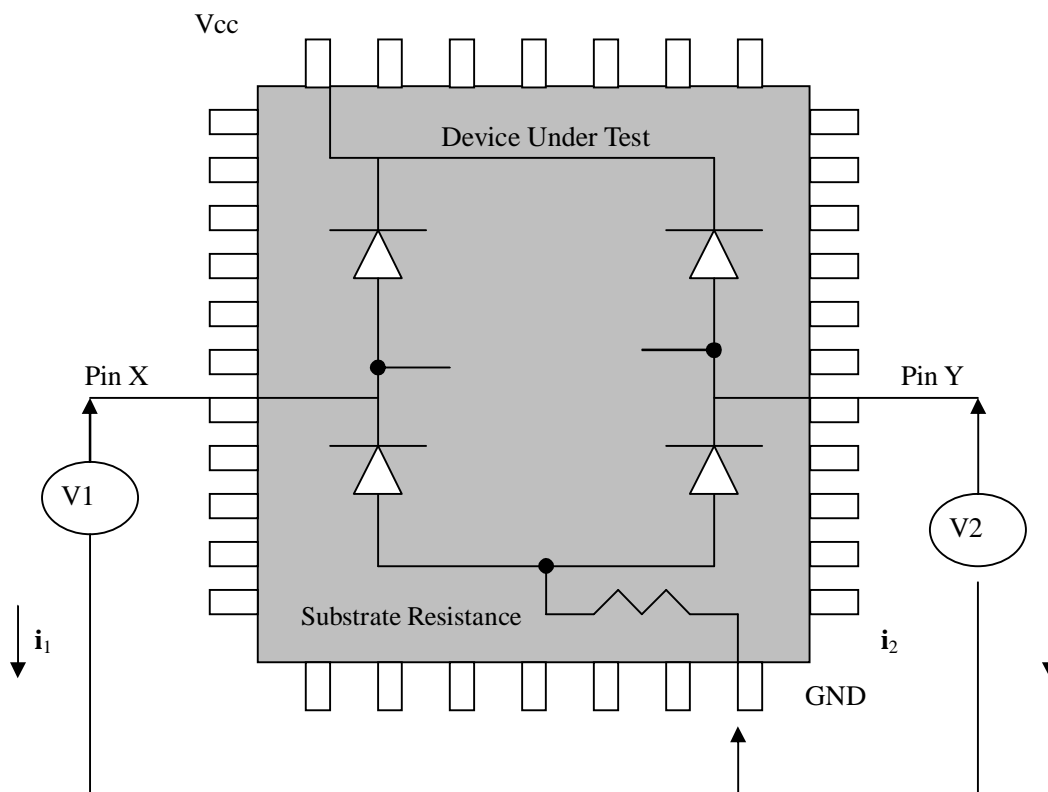


T623F Additional Feature: eScan



eScan Vectorless IC Test

eScan is a comprehensive vectorless IC test that it provides fast programming, high fault coverage and accurate pin-level diagnostics without requiring traditional in-circuit vectors and additional hardware. Test programming using eScan takes a minute rather than the days needed to develop in-circuit test patterns using traditional methods. Most digital devices and mixed-signal devices contain protection diodes. eScan performs comprehensive fault coverage over the entire SMT process fault spectrum and across different, package types, such as PLCC, BGA...etc.

Test with confidence

1. Apply drive voltage at PinX.
2. Measure i_1 .
3. Apply sense voltage at PinY.
4. Measure i_2 and compare with i_1 .
5. If i_1 not equals the value at "Learn" phase, PinX open
6. If i_1 equals i_2 , PinY open.